

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: March 22, 2002

ATTY DOCKET NO.
2001_1140ASERIAL NO.
09/927,328APPLICANT
Chicara KAWAMURA et al.FILING DATE
August 13, 2001GROUP
1714

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KIWL	AA	5,252,615	10/1993	Rao et al.	X	X	
KIWL	AB	3,951,886	4/1976	Miyake et al.	X	X	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

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MAR 28 2002
TC 1700

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
KIWL	AJ	11-228733	8/1999	JP	X	X	
	AK	50-61431	5/1975	JP	X	X	
	AL	2000-191766	7/2000	JP	X	X	
	AM	01/16208	3/2001	WO	X	X	
KIWL	AN	2,087,914	7/1993	CA (A1)	X	X	

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

AO	CIPO-Canadian Patent Database claims-2087914 (A1). FOREIGN DOCUMENT
AP	
AQ	

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DATE CONSIDERED

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KIML	AA	4,426,478	1/1984	Noyes et al.	X	X	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
KIML	AJ	01/62823	8/2001	WO	X	X		
KIML	AK	99/51431	10/1999	WO	X	X		
	AL							
	AM							
	AN							

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	AO	DATABASE WPI, Section Ch, Week 200136, Derwent Publications Ltd., London, GB; Class A23, AN 2001-337614 XP002199682 & JP 2001-001655 (1/2001) *abstract*.
	AP	→ These are foreign patents and should be placed above.
	AQ	

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DATE CONSIDERED